

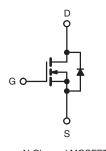
Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	950				
R _{DS(on)} (Ω)	V _{GS} = 10 V 5.4				
Q _g (Max.) (nC)	78				
Q _{gs} (nC)	9.6				
Q _{gd} (nC)	45				
Configuration	Single				

FEATURES

- Halogen-free According to IEC 61249-2-21 Definition
- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- · Fast Switching
- · Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC





N-Channel MOSFET

PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	950	v	
Gate-Source Voltage			V _{GS}	± 20	V	
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C	1	3	А	
		T _C = 100 °C	ID	1.8		
Pulsed Drain Current ^a			I _{DM}	10		
Linear Derating Factor				1.0	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	260	mJ	
Avalanche Current ^a			I _{AR}	3	А	
Repetitive Avalanche Energy ^a			E _{AR}	13	mJ	
Maximum Power Dissipation $T_{C} = 25 \text{ °C}$			PD	125	W	
Peak Diode Recovery dV/dt ^c			dV/dt	2.0	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	- °C	
Soldering Recommendations (Peak Temperature) for 10 s				300 ^d		
Mounting Torque	6.20	12 oorou		10	lbf ∙ in	
Mounting Torque	6-32 or M3 screw			1.1	N·m	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD} = 50$ V, starting $T_J = 25$ °C, L = 29 mH, $R_g = 25 \Omega$, $I_{AS} = 4.1$ A (see fig. 12). c. $I_{SD} \le 4.1$ A, dl/dt ≤ 100 A/µs, $V_{DD} \le 600$ V, $T_J \le 150$ °C. d. 1.6 mm from case.



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	-	62		
Case-to-Sink, Flat, Greased Surface	R _{thCS}	-	0.50	-	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	-	1.0		

Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

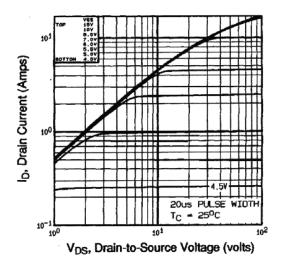
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							•
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_D = 250 \mu A$		950	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference	e to 25 °C, I _D = 1 mA	-	0.90	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μΑ	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	,	V _{GS} = ± 20 V	-	-	± 100	nA
		V _{DS} =	= 900 V, V _{GS} = 0 V	-	-	100	μA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 840 V	∕, V _{GS} = 0 V, T _J = 125 °C	-	-	500	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 2.5 A ^b	-	5.4	-	Ω
Forward Transconductance	9 _{fs}	V _{DS} =	= 100 V, I _D = 2.5 A	2.5	-	-	S
Dynamic						•	•
Input Capacitance	C _{iss}		V _{GS} = 0 V,		1300	-	
Output Capacitance	C _{oss}		$V_{DS} = 25 V,$	-	310	-	рF
Reverse Transfer Capacitance	C _{rss}	f = 1.	.0 MHz, see fig. 5	-	190	-	
Total Gate Charge	Qg		$V_{GS} = 10 \text{ V}$ $I_D = 4.1 \text{ A}, V_{DS} = 400 \text{ V},$ see fig. 6 and 13 ^b		-	78	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V			-	9.6	
Gate-Drain Charge	Q _{gd}			-	-	45	1
Turn-On Delay Time	t _{d(on)}	V_{DD} = 400 V, I_D = 4.1 A, R_g = 12 Ω, R_D = 95 Ω, see fig. $10^{\rm b}$		-	12	-	- ns
Rise Time	t _r			-	33	-	
Turn-Off Delay Time	t _{d(off)}			-	82	-	
Fall Time	t _f			-	30	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	
Internal Source Inductance	L _S			-	7.5	-	nH
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	4.1	A
Pulsed Diode Forward Current ^a	I _{SM}			-	-	16	
Body Diode Voltage	V_{SD}	$T_J = 25 \ ^\circ C, \ I_S = 4.1 \ A, \ V_{GS} = 0 \ V^b$		-	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	$T_{\rm J} = 25 ^{\circ}\text{C}, I_{\rm F} = 4.1 \text{A}, \text{dl/dt} = 100 \text{A/}\mu\text{s}^{\rm b}$		-	480	720	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	1.8	2.7	nC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L _S and L _D)				L _D)	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width \leq 300 µs; duty cycle \leq 2 %.





TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



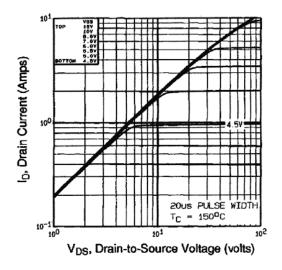


Fig. 2 - Typical Output Characteristics, $T_C = 150 \ ^{\circ}C$

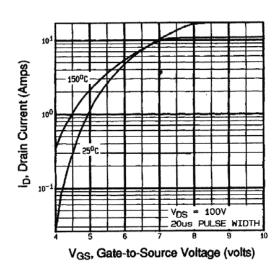


Fig. 3 - Typical Transfer Characteristics

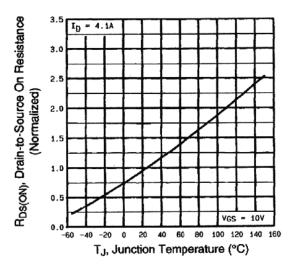


Fig. 4 - Normalized On-Resistance vs. Temperature



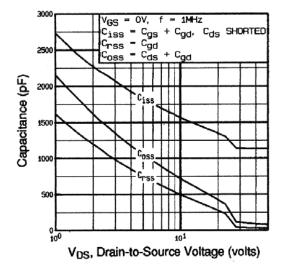


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

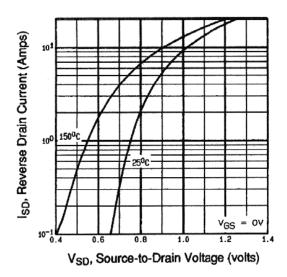


Fig. 7 - Typical Source-Drain Diode Forward Voltage

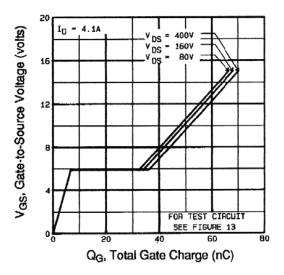
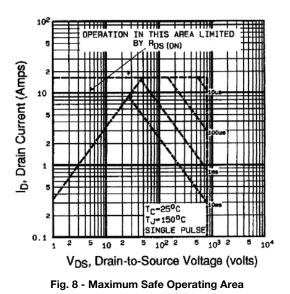


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage





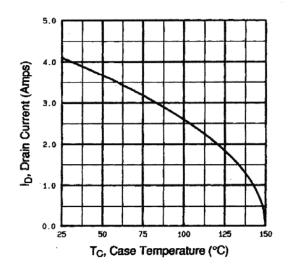


Fig. 9 - Maximum Drain Current vs. Case Temperature

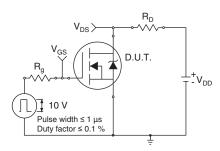


Fig. 10a - Switching Time Test Circuit

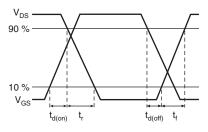
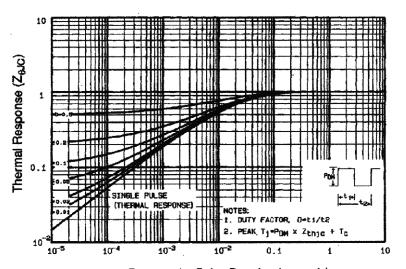


Fig. 10b - Switching Time Waveforms





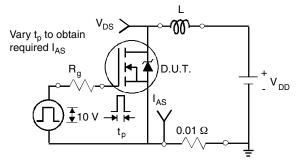


Fig. 12a - Unclamped Inductive Test Circuit

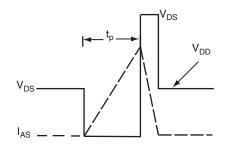


Fig. 12b - Unclamped Inductive Waveforms



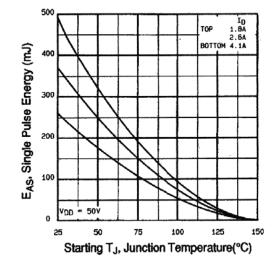


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

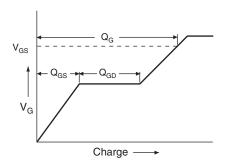


Fig. 13a - Maximum Avalanche Energy vs. Drain Current

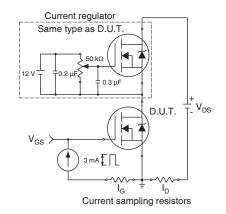
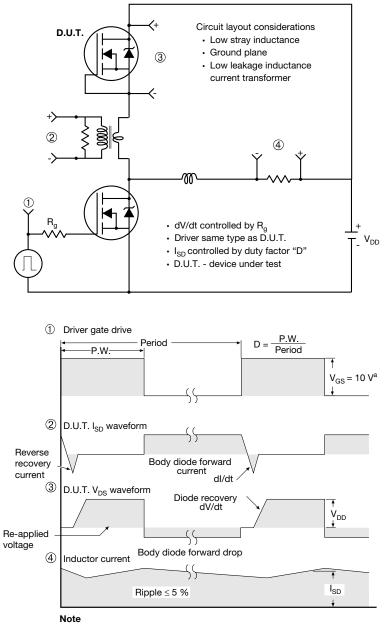


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

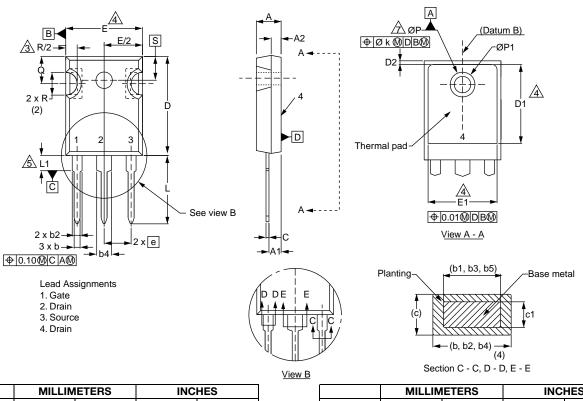


a. $V_{GS} = 5$ V for logic level devices

Fig. 14 - For N-Channel



TO-247AC (High Voltage)



	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
A	4.58	5.31	0.180	0.209
A1	2.21	2.59	0.087	0.102
A2	1.17	2.49	0.046	0.098
b	0.99	1.40	0.039	0.055
b1	0.99	1.35	0.039	0.053
b2	1.53	2.39	0.060	0.094
b3	1.65	2.37	0.065	0.093
b4	2.42	3.43	0.095	0.135
b5	2.59	3.38	0.102	0.133
С	0.38	0.86	0.015	0.034
c1	0.38	0.76	0.015	0.030
D	19.71	20.82	0.776	0.820
D1	13.08	-	0.515	-
				<u>.</u>

	MILLIM	IETERS	INC	HES	
DIM.	MIN.	MAX.	MIN.	MAX.	
D2	0.51	1.30	0.020	0.051	
E	15.29	15.87	0.602	0.625	
E1	13.72	-	0.540	-	
е	5.46	BSC	0.215	BSC	
Øk	0.254		0.0	0.010	
L	14.20	16.25	0.559	0.640	
L1	3.71	4.29	0.146	0.169	
N	7.62 BSC		0.300 BSC		
ØΡ	3.51	3.66	0.138	0.144	
Ø P1	-	7.39	-	0.291	
Q	5.31	5.69	0.209	0.224	
R	4.52	5.49	0.178	0.216	
S	5.51 BSC		0.217 BSC		



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